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United States Patent [19]

Elie

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[45] Date of Patent: ** Jun. 16, 1992

[54] **REFRACTOMETER**

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[**] Term: **14 Years**

[21] Appl. No.: **542,416**

[22] Filed: **Jun. 22, 1990**

[30] **Foreign Application Priority Data**

Dec. 29, 1989 [FR] France 898 145

[52] **U.S. Cl.** **D10/46;** D10/75; D24/172

[58] **Field of Search** D10/46, 75; D24/172; 356/128, 129, 130, 131, 132, 133, 134, 135, 136, 137

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for a refractometer, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a refractometer showing my new design;
FIG. **2** is a right side elevational view;
FIG. **3** is a front elevational view;
FIG. **4** is a left side elevational view;
FIG. **5** is a rear elevational view;
FIG. **6** is a top bottom view; and,
FIG. **7** is a bottom plan view thereof.
FIG. **1** has been drawn on a slightly reduced scale with respect to FIGS. **2-7.**

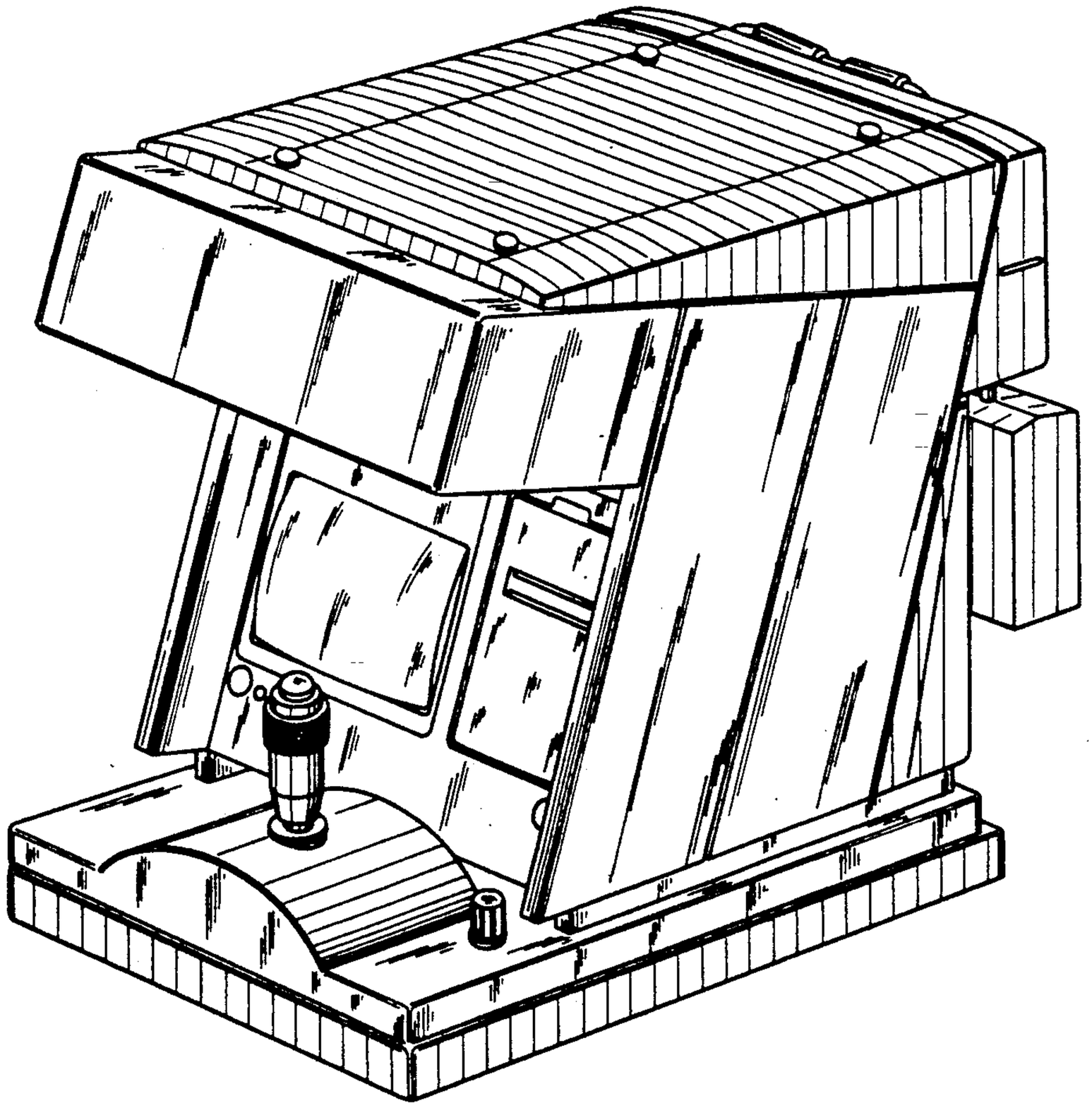

FIG. 1

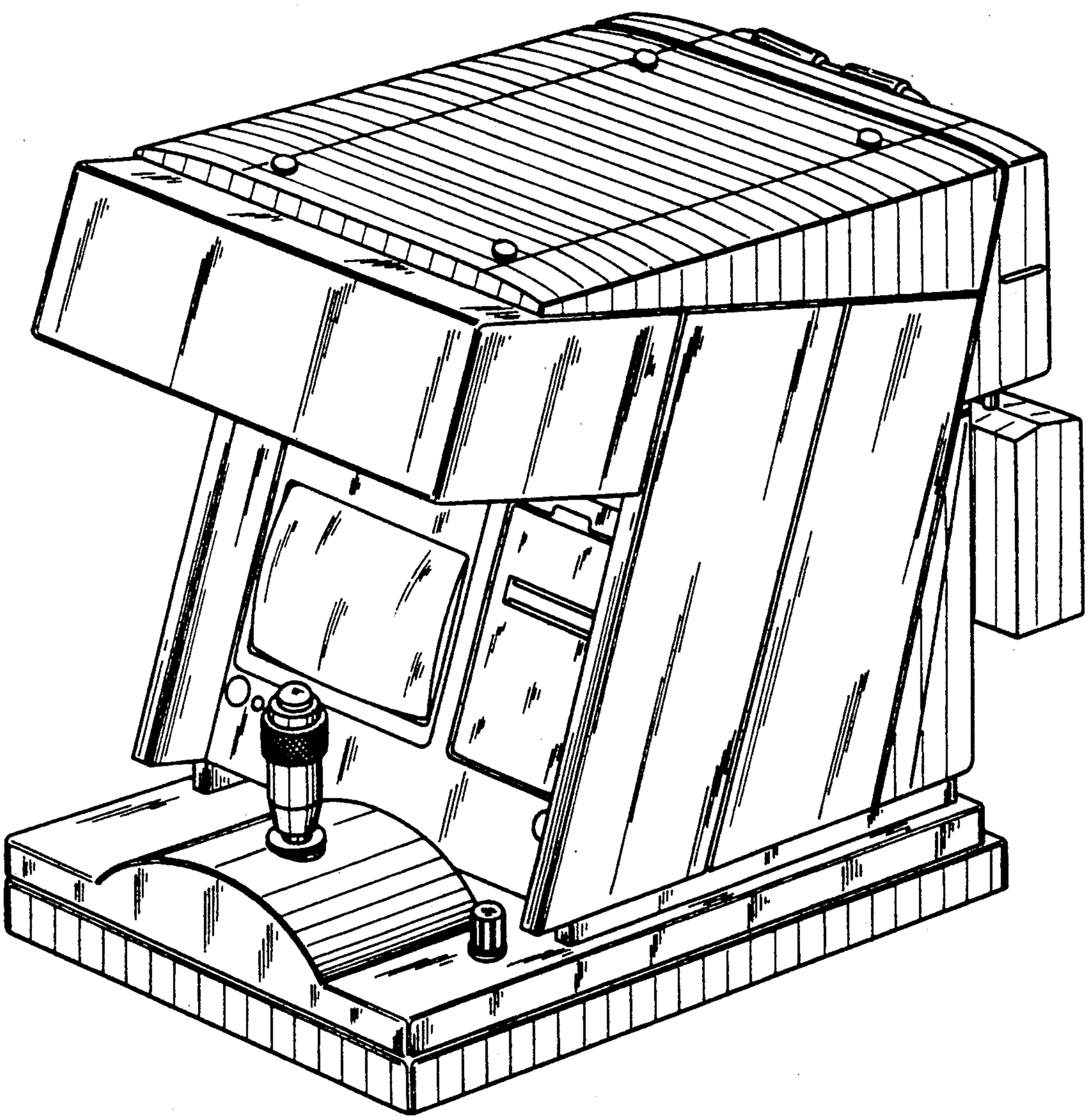

FIG. 2

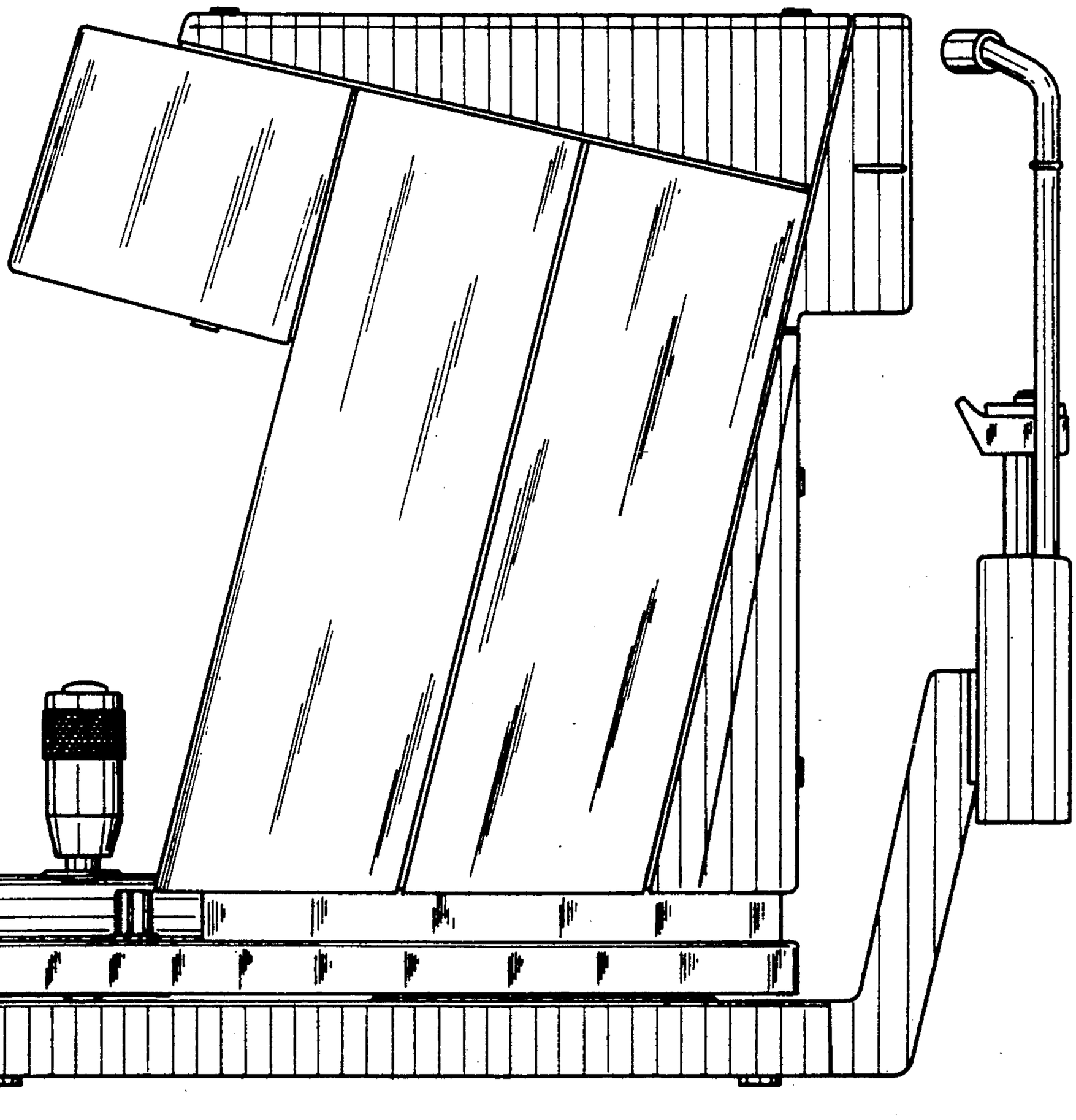

FIG. 3

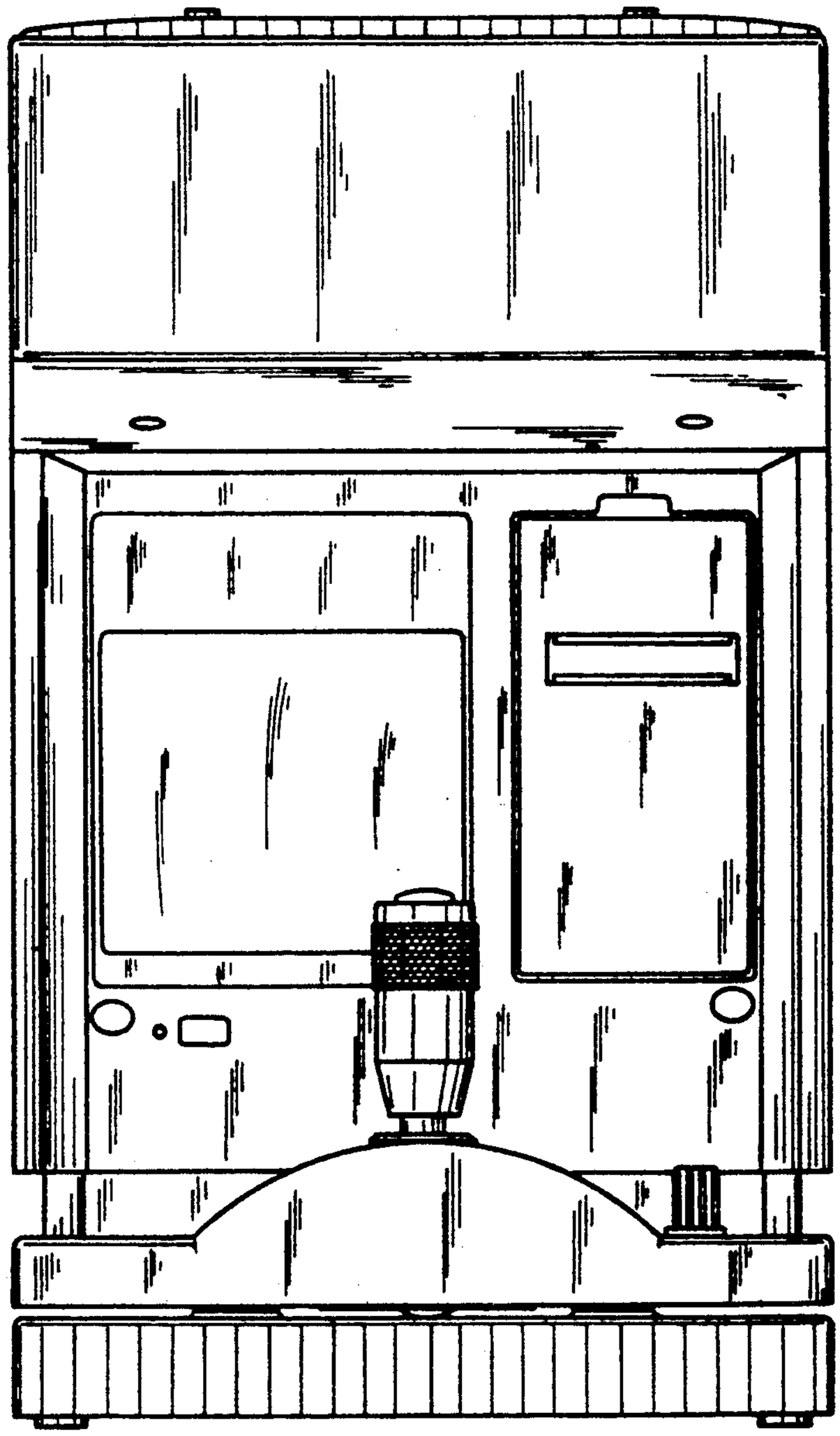

FIG. 4

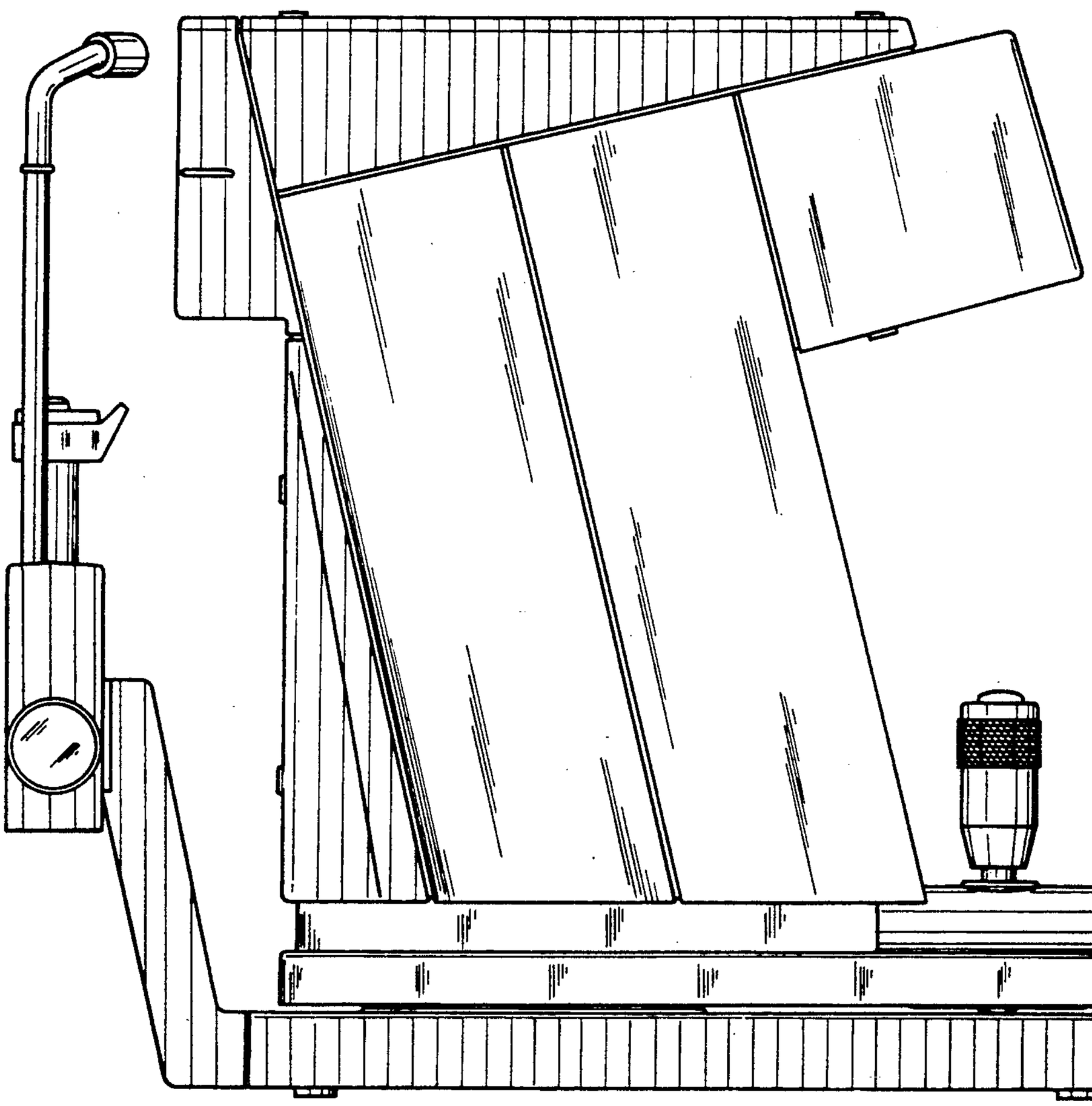

FIG.5

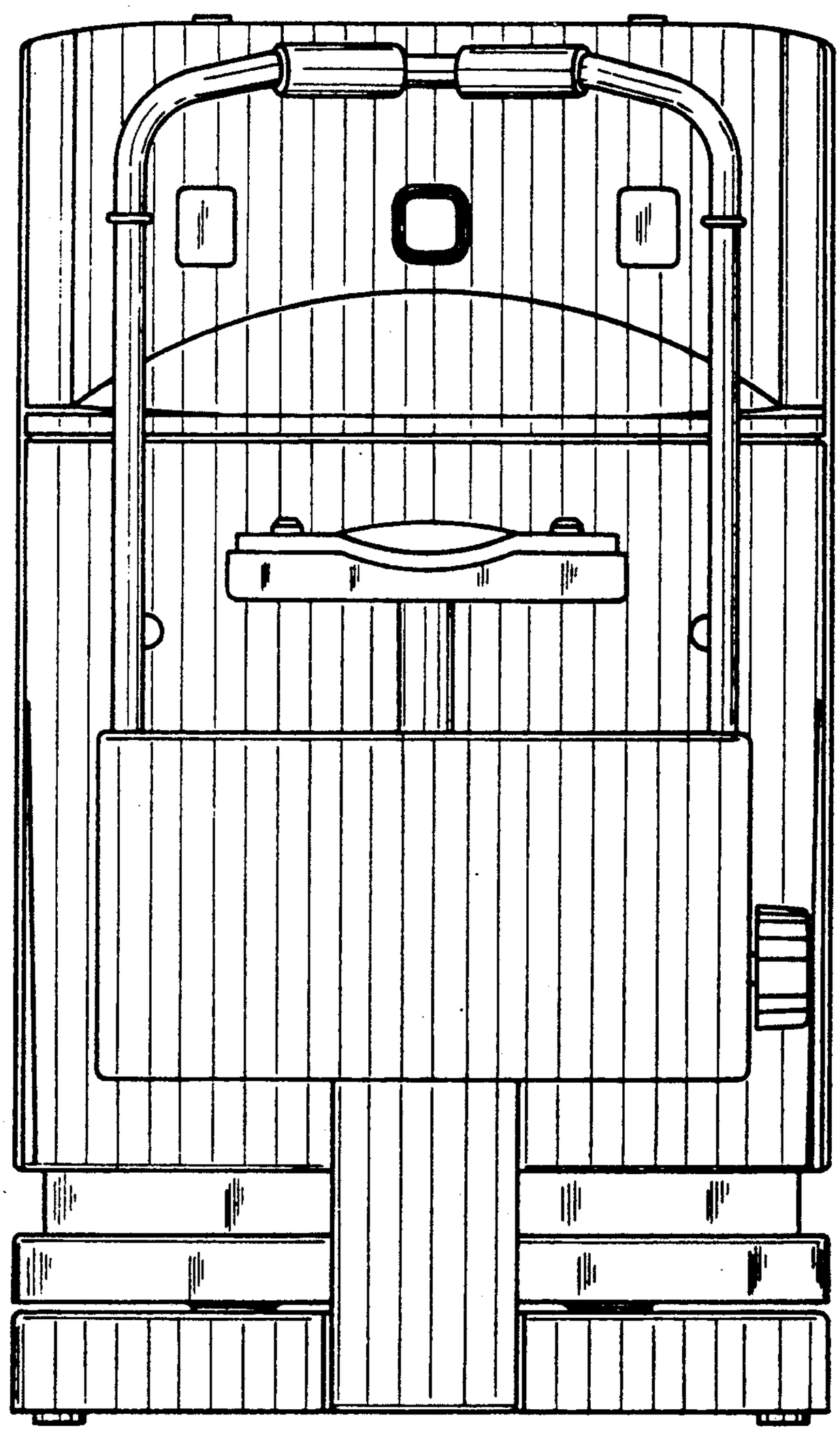

FIG. 6

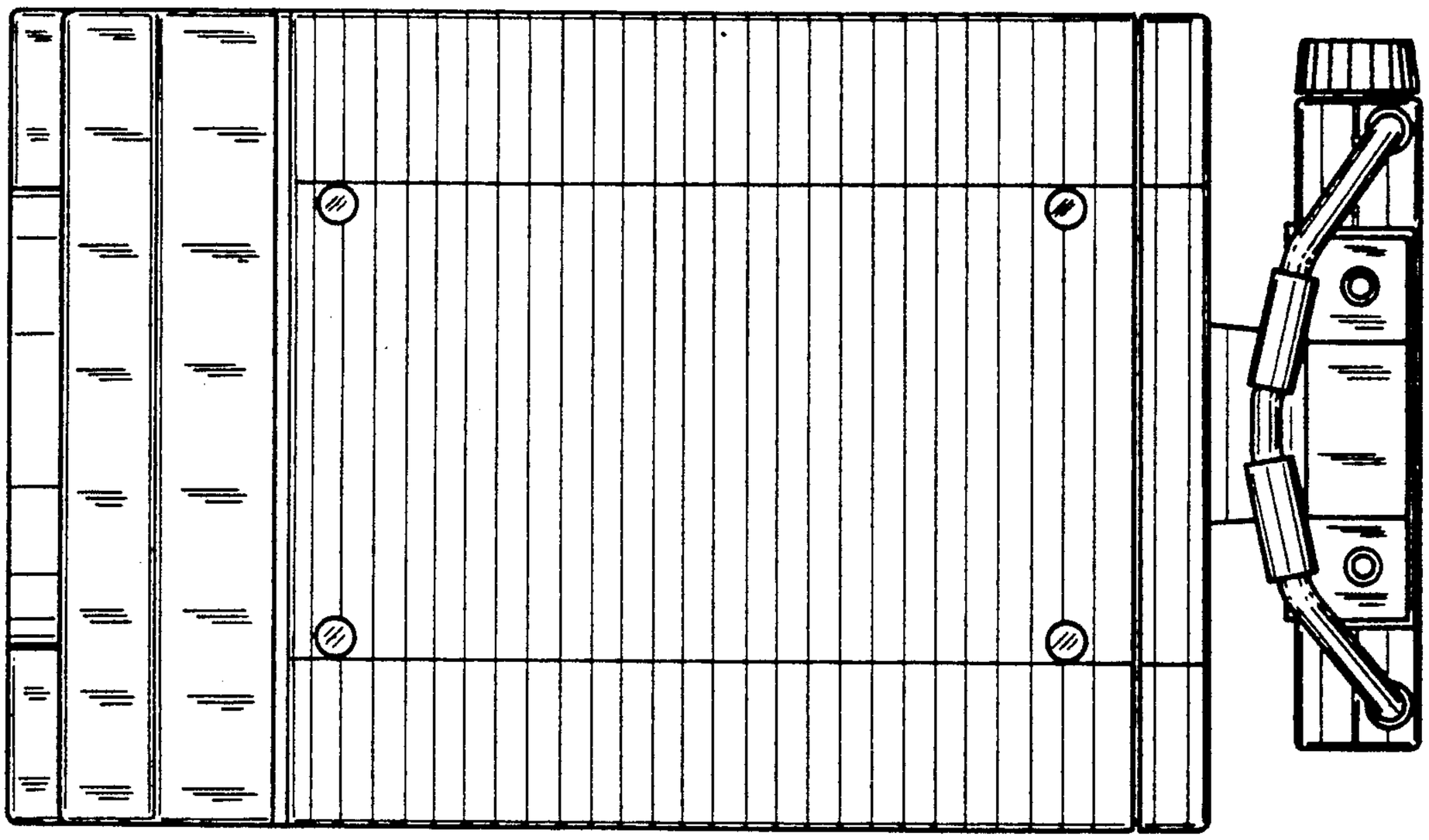

FIG. 7